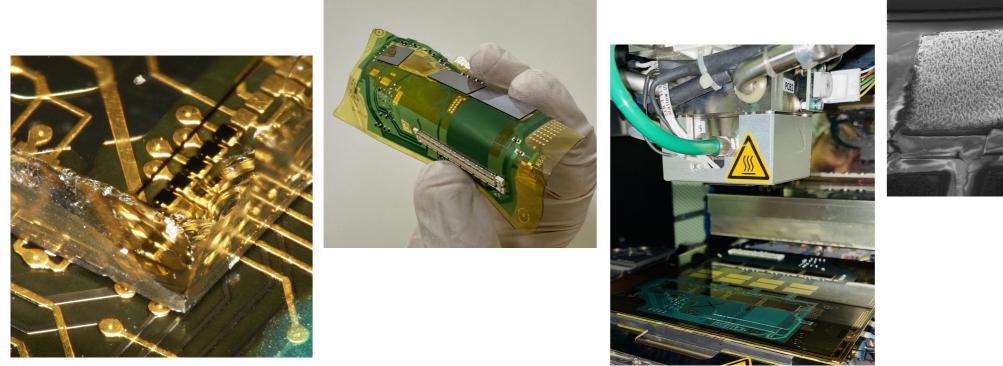
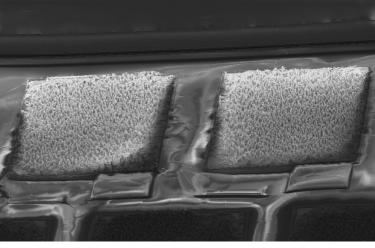
Development of a Novel Low-Mass Flip-Chip-Capable Module Flex PCB

Mateus Vicente Barreto Pinto, Milou Van Rijnbach, Florian Dachs, Valerio Dao, Carlos Solans Sanchez, Heinz Pernegger, Dominik Dannheim, Abhishek

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Thin film Elovible DCP	 Concept and design
	• First electrical and mechanical tests

Interconnection technologies	OverviewPre-bonding verification
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Results and Outlook

- Forceless flex detachment
- Further development

Goal: Flexible, low material, dense and reliable modules

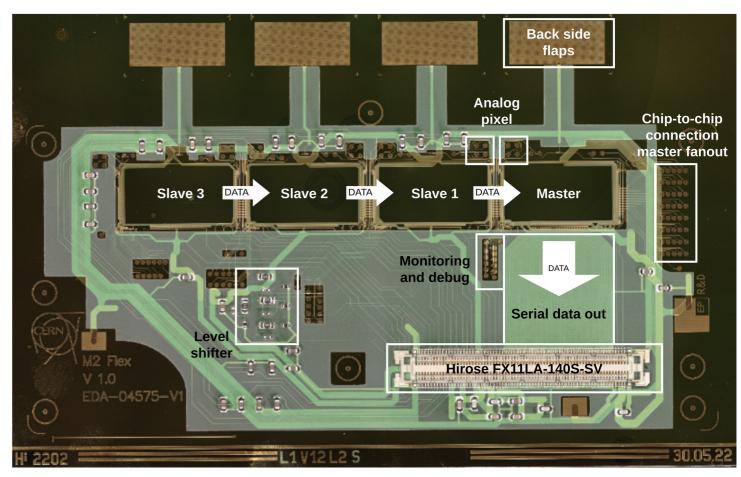


Flex Demonstrator Overview



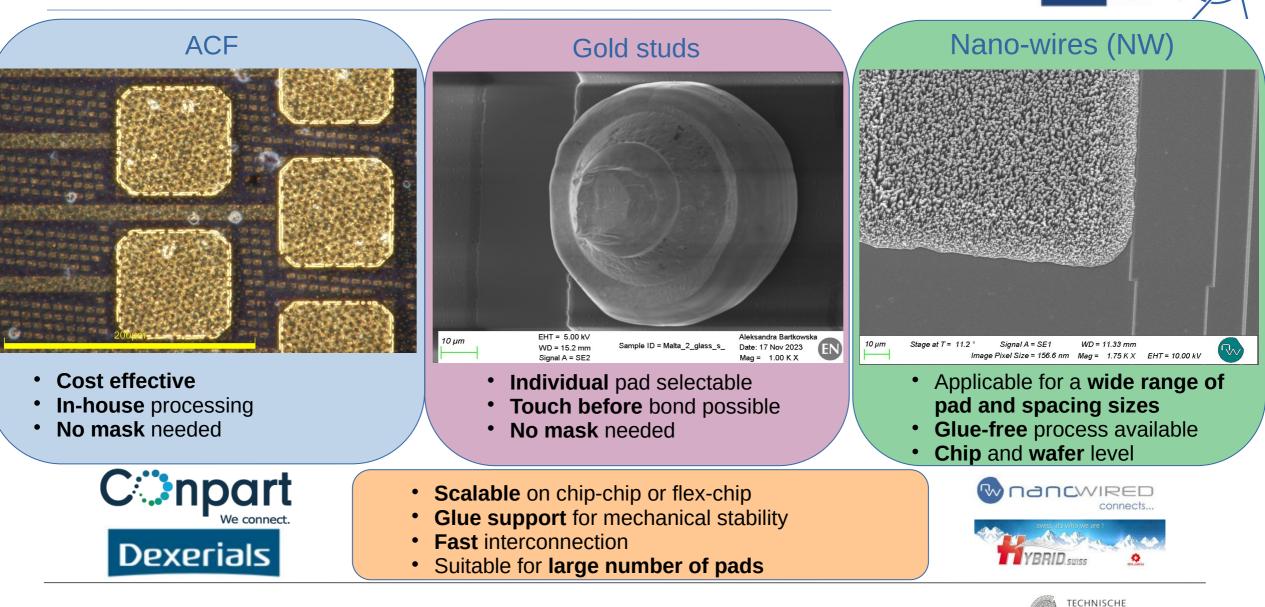
The manufactured flex provides:

- Manufacturing **low-mass**, highly flexible PCB
- Demonstrating a dense integration of silicon pixel chips
- **Two-layer** layout ~30µm high with 17µm trace width and spacing
- Data transfer from chip-to-chip
- Individual powering with 500mA per chip
- 140 pin connector for lab tests
- Integrated back side flaps providing bias voltage
- Inclusion of debug pads and data fan-outs





Interconnection Technologies for Flip-chip



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4/14

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In-situ verification



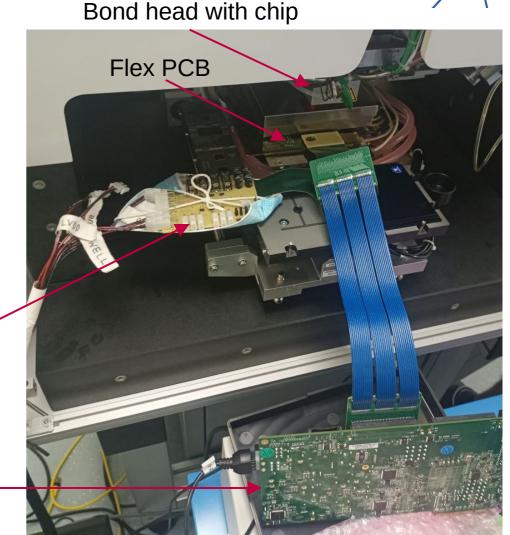
- **Pre-bonding verification** is a crucial part on the track to flip chip modularization of large modules
- Successfully tested full pre-bond verification with powering and reading out chip before bonding
- Compatible with gold studs and nano-wires
- Automation for a larger scale production foreseen

Process steps:

- 1) **Connect** Flex to power and read out
- 2) Align chip on bonehead with flex pads
- 3) Hold chip on flex with 0.5 x bond force
- 4) Power up chip and run tests
- 5) If chip OK, start **bonding** procedure, else replace

Power delivery board

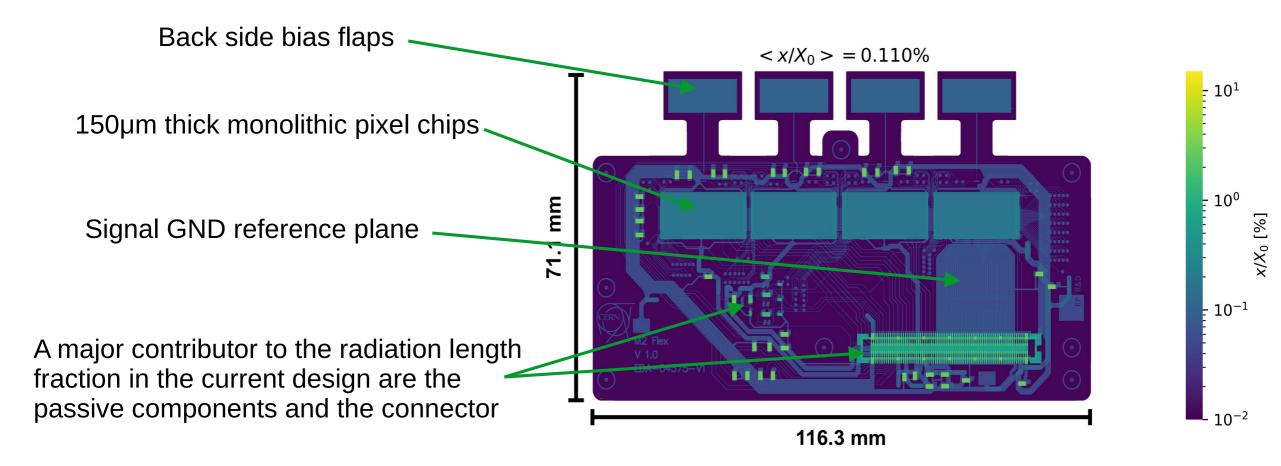
Read out FPGA





Calculated Material Budget

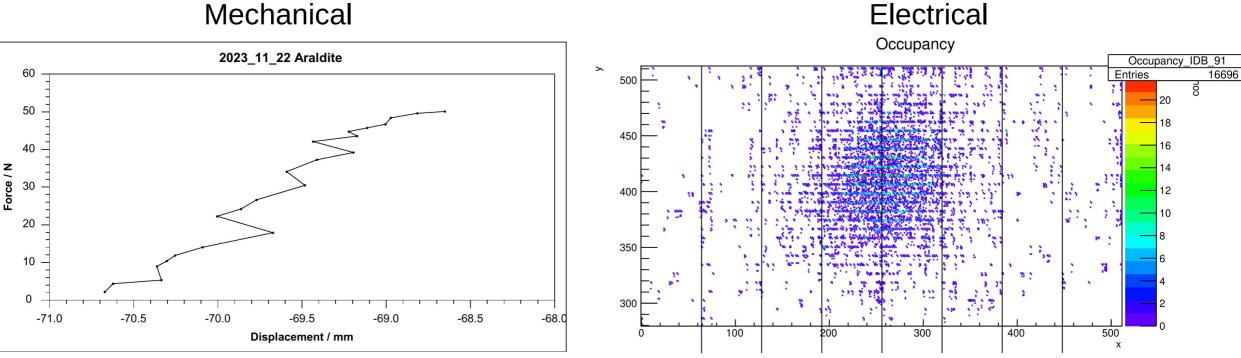






First Tests



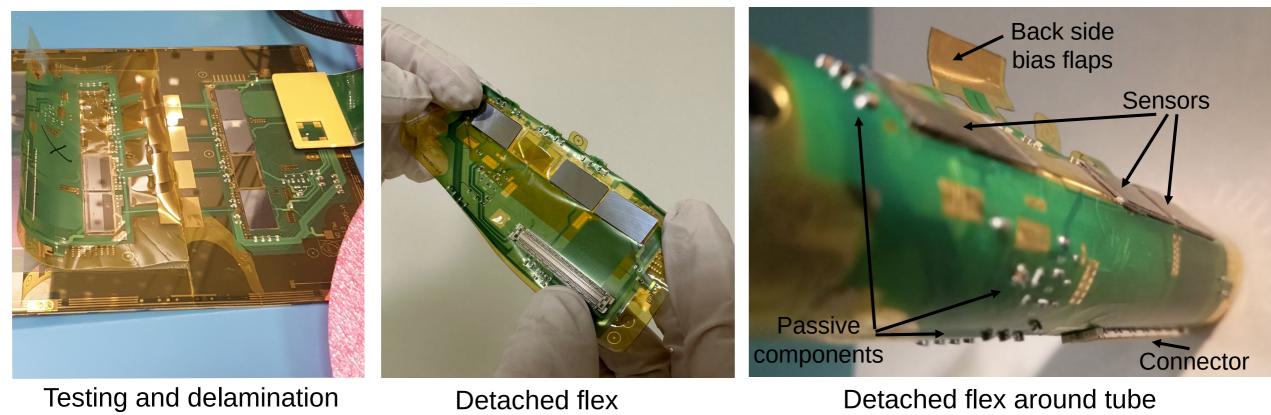


- Araldite 2011 as under fill
- **Pull force** to detach a chip from the flex **>50N**
- The used under fill is **compatible** with all shown interconnection technologies
- Hit map of a Sr90 source on master chip bonded to flex
- Demonstrating a **successful communication** with the chip



Detaching Flex

- EP R&D
- Detachment from production carrier conducted after flex assembly
- Force needed for the detachment process, resulting in tension onto the polyamide
- Bonding on production carrier **preserves tolerances** during assembly

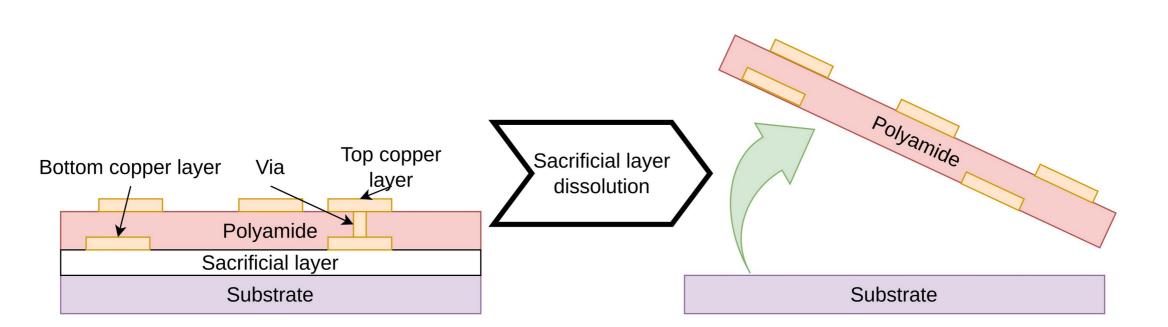




8/14

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Forceless flex-carrier separation



- Forceless separation process reducing stresses of the flex during detachment
- Reducing mechanical deformation of the flex during the separation process
- Potentially enabling the manufacturing of pads on top and bottom of the flex
- Reducing manual labor in large scale manufacturing processes
- In a first try, **aluminum** is used as sacrificial layer and **removed by electrolytic corrosion**



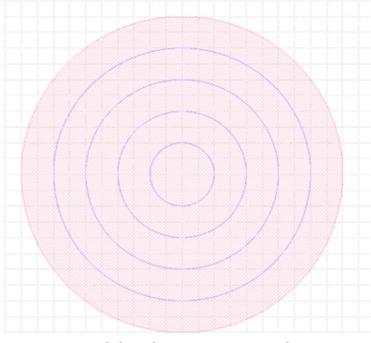
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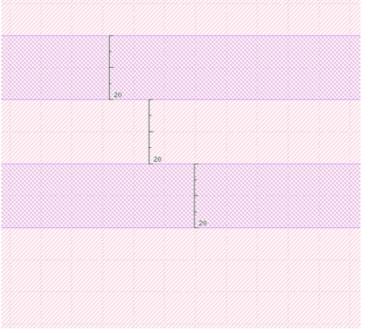
Separation prototype - design



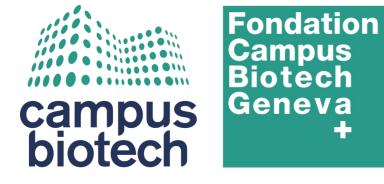
- Flex manufactured on 4 inch wafer
- 4 double ring construction
- Testing the manufactur ability of 20µm track width and spacing
- Testing forceless detachment
- Manufactured by the summer student Maria Sousa at **Campus Biotech**



Double ring on 4" wafer



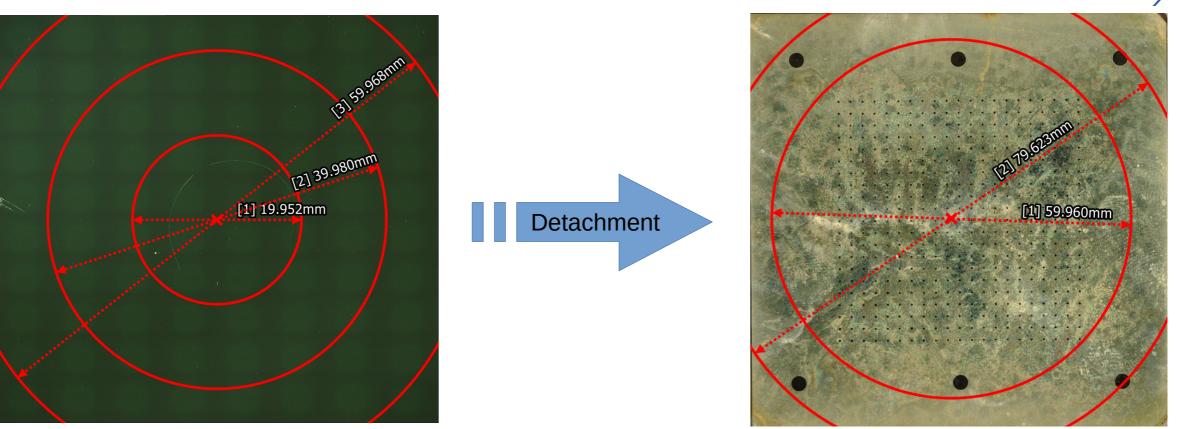
$20 \mu m$ track width and spacing





10/14

Separation prototype - detachment tests



- Circular test structure on 8µm polyamide flex before and after forceless detachment
- Forceless separation of single layer flex successfully demonstrated
- First tests show a **deformation of <0.5%**

EP

R&D

Towards custom fully integrated circuits

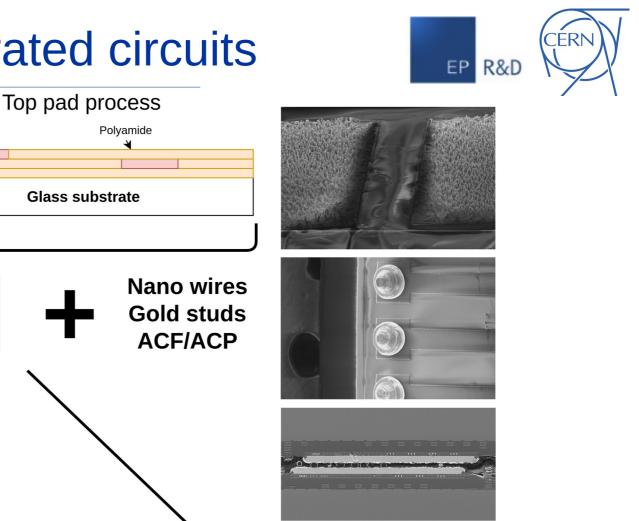
Separation

layer

Top and bottom pad process

Polyamide

Copper



Glass substrate Development of in-house prototyping of flex utilizing 20/20 technology. Integration of monolithic sensors Integration of hybrid sensors ASIC ASIC Sensor **Glass substrate** Glass substrate TECHNISCHE UNIVERSITÄT

Copper

Dec 2, 2024

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To sum it up



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Interconnection technologies	 Three interconnection options Pre-bond verification with gold studs

Results and Outlook

- Forceless flex detachment process
- Further developments on the prebond verification

-> Flexible framework for the modularization of pixel chips







Thank you very much for your attention



14/14